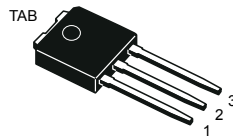
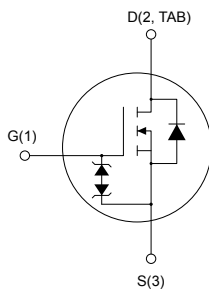


## N-channel 800 V, 0.95 $\Omega$ typ., 6 A MDmesh K5 Power MOSFET in an IPAK package


**IPAK**


AM01476v1\_tab


**Product status link**
[STU7N80K5](#)
**Product summary**

<b>Order code</b>	STU7N80K5
<b>Marking</b>	7N80K5
<b>Package</b>	IPAK
<b>Packing</b>	Tube

### Features

Order code	$V_{DS}$	$R_{DS(on)}$ max.	$I_D$
STU7N80K5	800 V	1.2 $\Omega$	6 A

- Industry's lowest  $R_{DS(on)}$  x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications

### Description

This very high voltage N-channel Power MOSFET is designed using MDmesh K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 30$	V
$I_D$	Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$	6	A
	Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$	3.8	
$I_{DM}^{(1)}$	Drain current (pulsed)	24	A
$P_{TOT}$	Total power dissipation at $T_C = 25\text{ }^\circ\text{C}$	110	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	4.5	V/ns
$dv/dt^{(3)}$	MOSFET $dv/dt$ ruggedness	50	V/ns
$T_{stg}$	Storage temperature range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating junction temperature range		$^\circ\text{C}$

1. Pulse width is limited by safe operating area.
2.  $I_{SD} \leq 6\text{ A}$ ,  $di/dt \leq 100\text{ A}/\mu\text{s}$ ,  $V_{DS}(\text{peak}) < V_{(BR)DSS}$ .
3.  $V_{DS} \leq 640\text{ V}$ .

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance, junction-to-case	1.14	$^\circ\text{C}/\text{W}$
$R_{thJA}$	Thermal resistance, junction-to-ambient	100	$^\circ\text{C}/\text{W}$

**Table 3. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or non-repetitive (pulse width limited by $T_J$ max.)	2	A
$E_{AS}$	Single pulse avalanche energy (starting $T_J = 25\text{ }^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	88	mJ

## 2 Electrical characteristics

$T_C = 25\text{ °C}$  unless otherwise specified.

**Table 4. On/off-state**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$ , $I_D = 1\text{ mA}$	800			V
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 800\text{ V}$ , $V_{GS} = 0\text{ V}$			1	$\mu\text{A}$
		$V_{DS} = 800\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_C = 125\text{ °C}^{(1)}$			50	
$I_{GSS}$	Gate body leakage current	$V_{GS} = \pm 20\text{ V}$ , $V_{DS} = 0\text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 100\text{ }\mu\text{A}$	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$ , $I_D = 3\text{ A}$		0.95	1.2	$\Omega$

1. Specified by design, not tested in production.

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0\text{ V}$	-	360	-	pF
$C_{oss}$	Output capacitance		-	30	-	pF
$C_{rss}$	Reverse transfer capacitance		-	1	-	pF
$C_{o(tr)}^{(1)}$	Equivalent capacitance time related	$V_{GS} = 0\text{ V}$ , $V_{DS} = 0\text{ to }640\text{ V}$	-	47	-	pF
$C_{o(er)}^{(2)}$	Equivalent capacitance energy related		-	20	-	pF
$R_g$	Intrinsic gate resistance	$f = 1\text{ MHz}$ open drain	-	6	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 640\text{ V}$ , $I_D = 6\text{ A}$ , $V_{GS} = 0\text{ to }10\text{ V}$ (see Figure 15. Test circuit for gate charge behavior)	-	13.4	-	nC
$Q_{gs}$	Gate-source charge		-	3.7	-	nC
$Q_{gd}$	Gate-drain charge		-	7.5	-	nC

1.  $C_{o(tr)}$  is a constant capacitance value that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

2.  $C_{o(er)}$  is a constant capacitance value that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 400\text{ V}$ , $I_D = 3\text{ A}$ , $R_G = 4.7\text{ }\Omega$ , $V_{GS} = 10\text{ V}$	-	11.3	-	ns
$t_r$	Rise time		-	8.3	-	ns
$t_{d(off)}$	Turn-off delay time	(see Figure 14. Test circuit for resistive load switching times and Figure 19. Switching time waveform)	-	23.7	-	ns
$t_f$	Fall time		-	20.2	-	ns

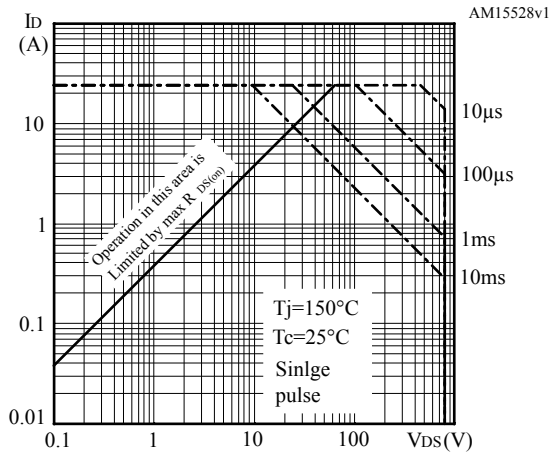
**Table 7. Source-drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		6	A
$I_{SDM}$	Source-drain current (pulsed)		-		24	A
$V_{SD}^{(1)}$	Forward on voltage	$I_{SD} = 6\text{ A}$ , $V_{GS} = 0\text{ V}$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 6\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,	-	315		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 60\text{ V}$	-	2.8		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	17.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 6\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,	-	480		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 60\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$	-	3.8		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	16		A

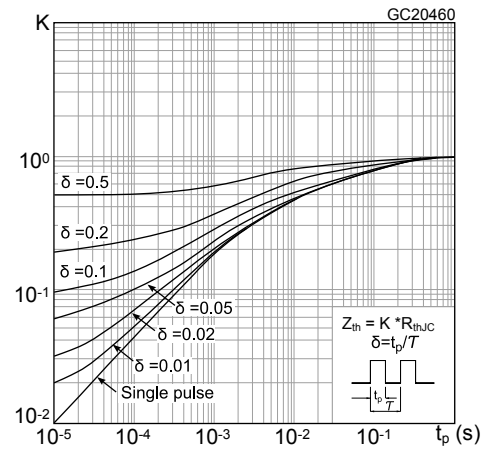
1. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

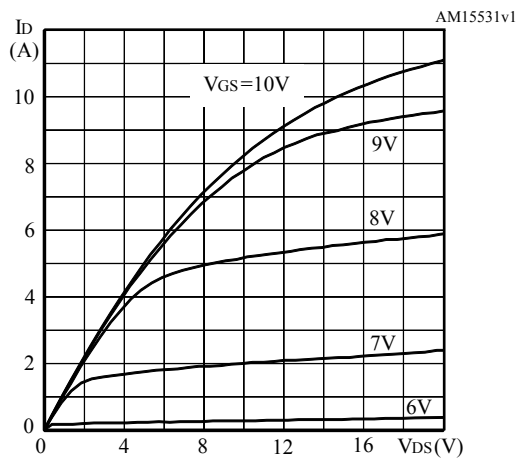
**Figure 1. Safe operating area**



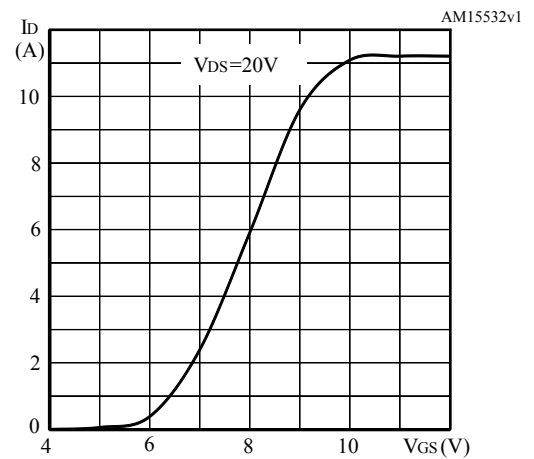
**Figure 2. Normalized transient thermal impedance**



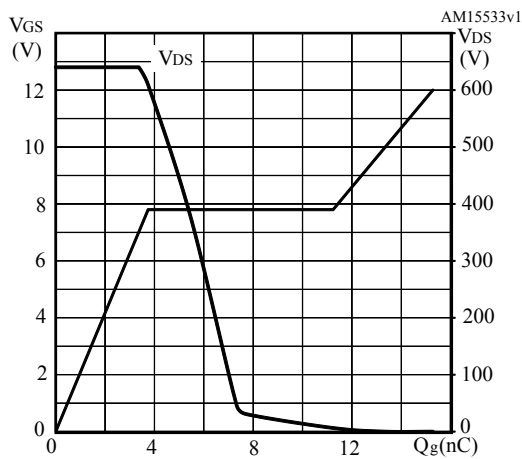
**Figure 3. Typical output characteristics**



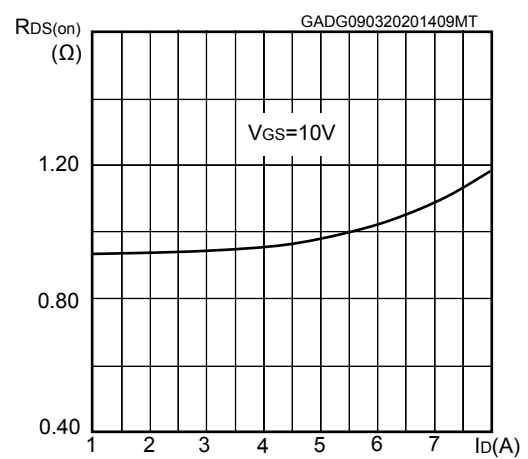
**Figure 4. Typical transfer characteristics**



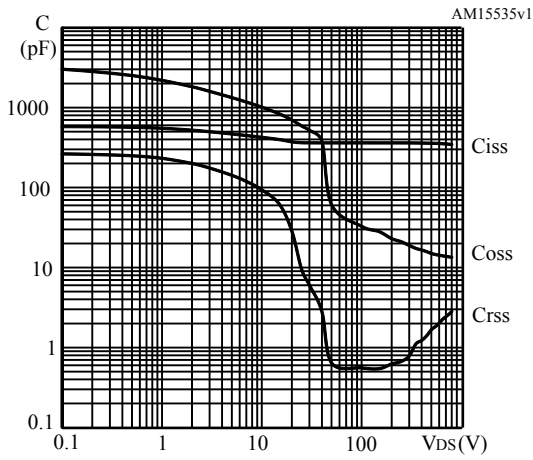
**Figure 5. Typical gate charge characteristics**



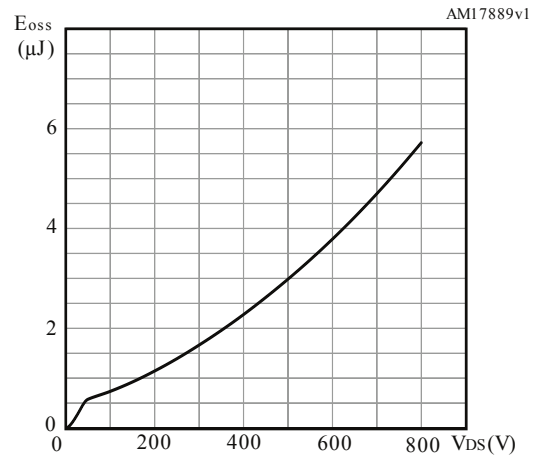
**Figure 6. Typical drain-source on-resistance**



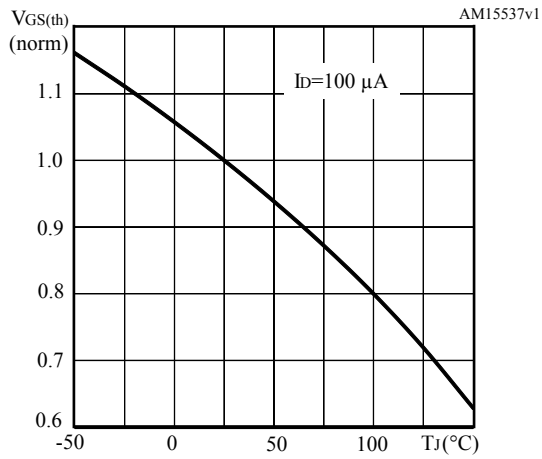
**Figure 7. Typical capacitance characteristics**



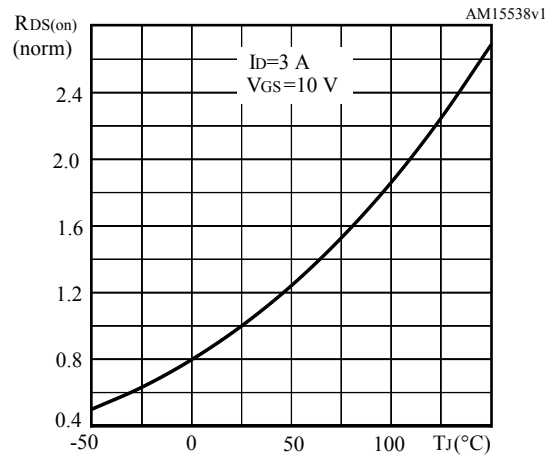
**Figure 8. Typical output capacitance stored energy**



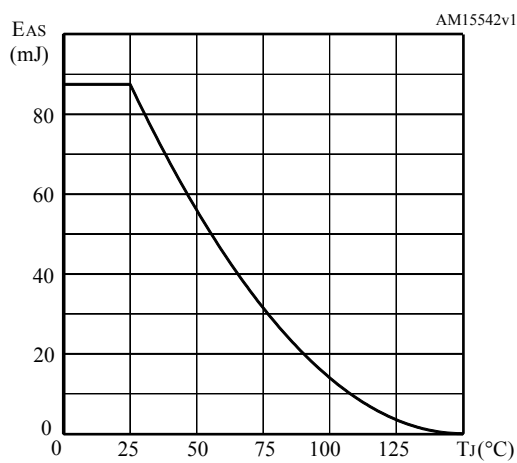
**Figure 9. Normalized gate threshold vs temperature**



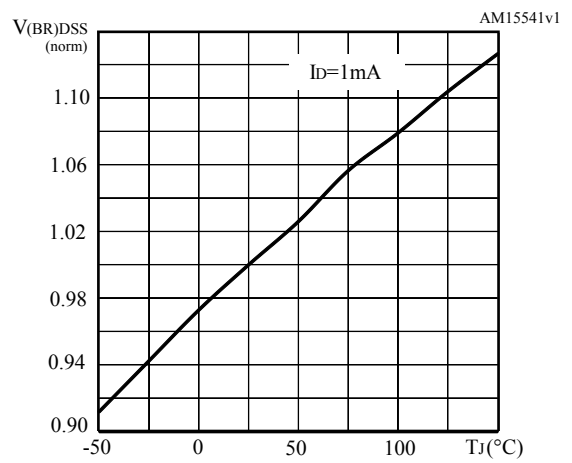
**Figure 10. Normalized on-resistance vs temperature**



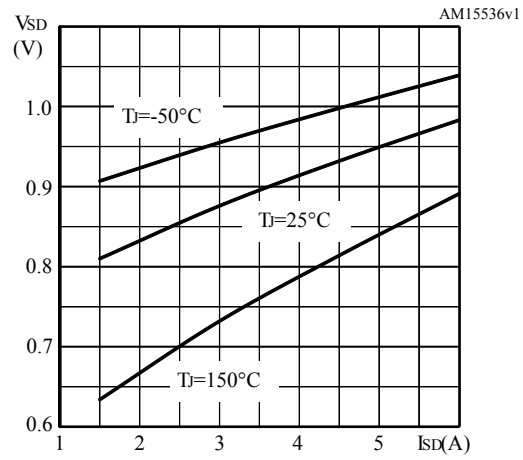
**Figure 11. Maximum avalanche energy vs starting Tj**



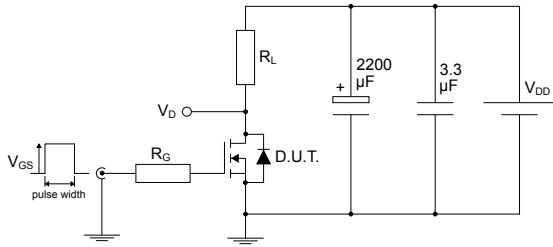
**Figure 12. Normalized breakdown voltage vs temperature**



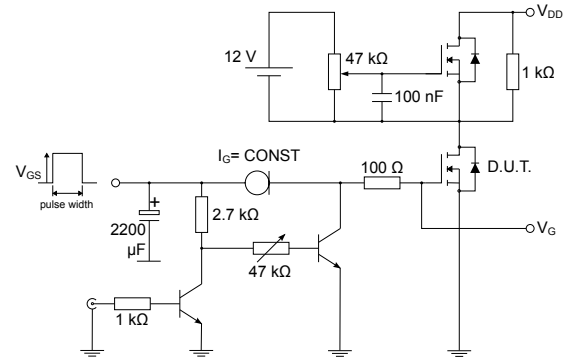
**Figure 13. Typical reverse diode forward characteristics**



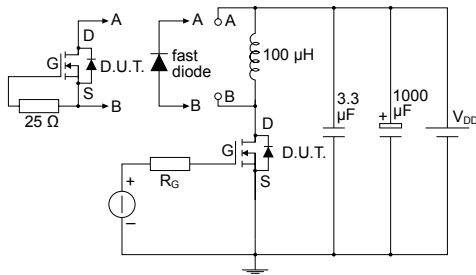
### 3 Test circuits

**Figure 14. Test circuit for resistive load switching times**


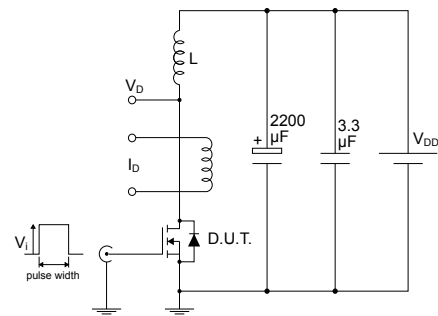
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**Figure 15. Test circuit for gate charge behavior**


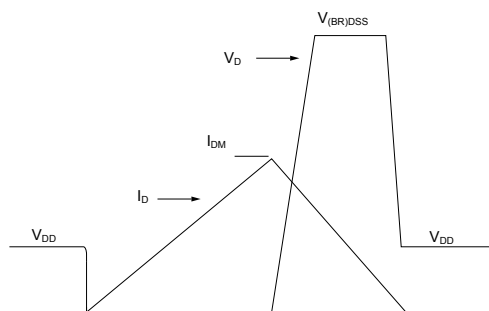
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**Figure 16. Test circuit for inductive load switching and diode recovery times**


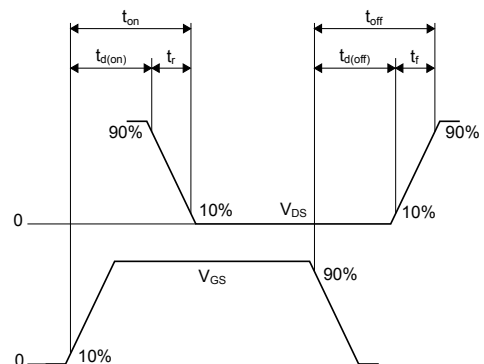
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**Figure 17. Unclamped inductive load test circuit**


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**Figure 18. Unclamped inductive waveform**


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**Figure 19. Switching time waveform**


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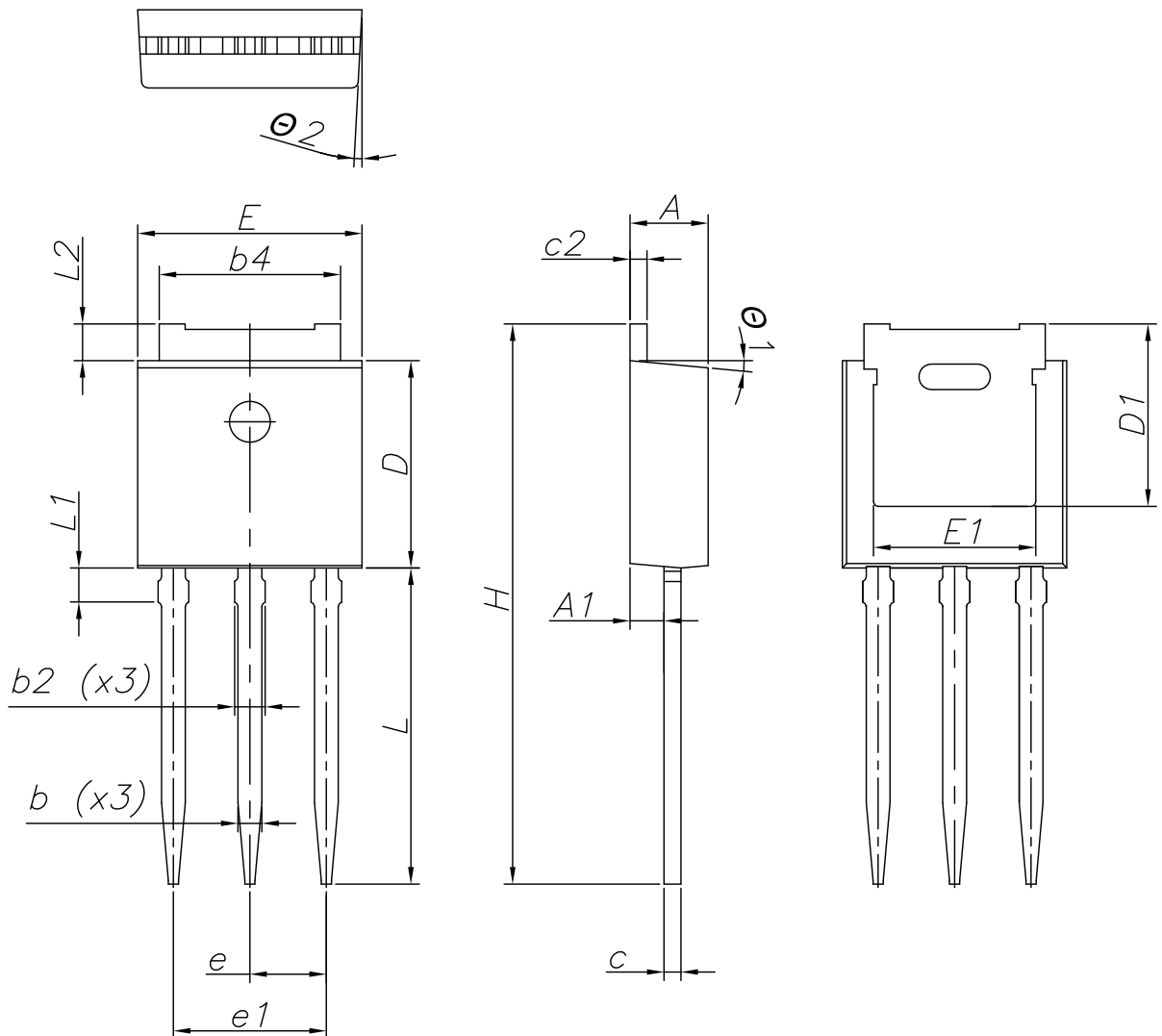


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 IPAK (TO-251) type C package information

Figure 20. IPAK (TO-251) type C package outline



0068771\_IK\_typeC\_rev16

**Table 8. IPAK (TO-251) type C package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.35
A1	0.90	1.00	1.10
b	0.66		0.79
b2			0.90
b4	5.23	5.33	5.43
c	0.46		0.59
c2	0.46		0.59
D	6.00	6.10	6.20
D1	5.20	5.37	5.55
E	6.50	6.60	6.70
E1	4.60	4.78	4.95
e	2.20	2.25	2.30
e1	4.40	4.50	4.60
H	16.18	16.48	16.78
L	9.00	9.30	9.60
L1	0.80	1.00	1.20
L2	0.90	1.08	1.25
θ1	3°	5°	7°
θ2	1°	3°	5°

## Revision history

**Table 9. Document revision history**

Date	Revision	Changes
19-Sep-2023	1	First release. Part number STU7N80K5 previously included in datasheet DS9173.

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